

PCN#20230927001.1 Qualification of additional Fab site (RFAB) using qualified Process Technology and additional BOM options for select devices Change Notification / Sample Request

Date: September 28, 2023 To: PREMIER FARNELL PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments (TI). The details of this change are on the following pages, and are in alignment with our standard product change notification (PCN) <u>process</u>.

TI requires acknowledgement of receipt of this notification within 30 days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance and approval of this change. If samples or additional data are required, requests must be received within 30 days of this notification, given that samples are not built ahead of the change.

The Proposed First Ship date in this PCN letter is the earliest possible date that customers could receive the changed material. It is our commitment that the changed device will not ship before that date. If samples are requested within the 30 day sample request window, customers will still have 30-days to complete their evaluation regardless of the proposed 1st ship date.

This particular PCN is related to TI's multiyear transition plan for our two remaining factories with 150-millimeter production (DFAB in Dallas, Texas, and SFAB in Sherman, Texas). DFAB will remain open, but will focus on 200-mm production, with a smaller set of technologies. SFAB will close no earlier than 2024 and no later than 2025. As referenced in the "reason for change" below, these changes are part of our multiyear plan to transition these products to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the Change Management team. For sample requests or sample related questions, contact your local Field Sales Representative. As always, we thank you for your continued business.

Change Management Team SC Business Services

20230927001.1 Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, you have recently purchased these devices. The corresponding customer part number is also listed, if available.

DEVICE

UA78L12ACPK

CUSTOMER PART NUMBER null

Technical details of this Product Change follow on the next page(s).

								-	
PCN Num	ber:	202	30927001.	1		PC	N Date		eptember 28,)23
Title:				site (RFAB) lect devices	using qualif	ied Pı	rocess	Fechno	ology and
Customer				anagement t	eam De	ept:		Qualit	ty Services
Proposed	1 st Ship	Date:	Dec 27, 2023 Sample accep					8, 2023*	
*Sample requests received after Oct 28, 2023 will not be supported.									
Change Ty						•			
Assemb	oly Site		Desig				Wafer	Bump	Material
	bly Proces			Sheet					Process
Assemb				number char	nge		Wafer		
	nical Spec		Test			\boxtimes			laterials
	J/Snippin	g/Labeling	l lest	Process		Ø	water	Fad P	rocess
				PCN Deta	ils				
Descriptio	on of Cha	ange:							
	the list o	of devices	in the produ	ict affected s	ection below	۷.			ditional BOM
Current Fab Site Additional Fab site									
		rrent r	ab Site				ional	Fab	
Curren	t Fab		N	/afer	Additio	nal			Wafer
Curren Sit	t Fab	Proces		/afer meter		nal	ional Proc		
	it Fab :e		ss W Dia		Additio	nal te		ess	Wafer
SH-B	it Fab e IP-1	Proces	s W Dia 15	meter	Additio Fab si RFAE	nal te	Proc	ess	Wafer Diameter
SH-B The die wa	it Fab ce IP-1 as also cl	Proces JI1 hanged as	s W Dia 15	ometer Omm	Additio Fab si RFAE	nal te	Proc	ess	Wafer Diameter
SH-B The die wa	it Fab ce IP-1 as also cl	Proces JI1 hanged as	a result of t	omm omm the process c	Additio Fab si RFAE	nal te	Proc	ess B	Wafer Diameter
SH-B The die wa	it Fab ce IP-1 as also cl	Proces JI1 hanged as	a result of t	ometer 50mm the process c	Additio Fab si RFAE hange.	nal te	Proc TI	ess B	Wafer Diameter
SH-B The die wa	IP-1 as also cl	Proces JI1 hanged as tions are r	a result of t oted below:	imeter 50mm the process c C SI	Additio Fab si RFAE hange.	nal te	Proc TI Additi	ess B onal R-27	Wafer Diameter
SH-B The die wa	IP-1 as also cl	Proces JI1 hanged as tions are r Mold Cor	a result of to oted below:	imeter 50mm the process c C SI Au,	Additio Fab si RFAE hange. urrent D#R-07	nal te	Proc TI Additi	ess B onal R-27 8 mil	Wafer Diameter
SH-B The die wa Additional	IP-1 as also cl BOM opt Bo Bo	Proces JI1 hanged as tions are r Mold Cor ond wire co diam Mount Co vided in th	a result of to oted below:	imeter iOmm the process c C SI Au, SII	Additio Fab si RFAE hange. urrent D#R-07 , 1.0 mil	nal te	Proc TI Additi SID#F	ess B onal R-27 8 mil	Wafer Diameter

factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

RoHS	REACH	Green Status	IEC 62474
🛛 No Change	🛛 No Change	🛛 No Change	🛛 No Change

Changes to product identification resulting from this PCN:

ab Site Informati Chip Site	on: Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site Cit
SH-BIP-1	SHE	USA	Sherman
RFAB	RFB	USA	Richa rdso r

Current	New		
Die Rev [2P]	Die Rev [2P]		
А	Α		

Product Affected:							
UA78L05ACPK	UA78L05CPK	UA78L12ACPK	UA78L15ACPK				
UA78L05AIPK							

For alternate parts with similar or improved performance, please visit the product page on $\underline{\text{TI.com}}$

TI Information Selective Disclosure

Qualification Report

UA78L Qual Approve Date 21-June-2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: <u>UA78L05ACPKM3</u>	Qual Device: <u>UA78L033AIPK</u>	Qual Device: <u>UA78L15ACPKM3</u>	QBS Process Reference: <u>MC33063ADR</u>	QBS Process Reference: <u>MC33063ADR</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/240/0	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	3/240/0	-	-
тс	A4	Temperature Cycle	-65C/150C	1000 Cycles	-	-	3/240/11	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	3/240/0	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	3/240/0	2/154/0	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	1/800/0	2/1600/0
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB- Free Solder;	-	-	-	1/22/0	-	-
ESD	E2	ESD CDM	-	250 Volts	-	-	1/3/0	-	-
ESD	E2	ESD HBM	-	1000 Volts	-	-	1/3/0	-	-

Туре	#	Test Name	Condition	Duration	Qual Device: <u>UA78L05ACPKM3</u>	Qual Device: <u>UA78L033AIPK</u>	Qual Device: <u>UA78L15ACPKM3</u>	QBS Process Reference: <u>MC33063ADR</u>	QBS Process Reference: <u>MC33063ADR</u>
LU	E4	Latch-Up	Per JESD78	-	-	-	1/6/0	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	-	-
FTY	E6	Final Test Yield	-	-	1/1/0	1/1/0	3/3/0	-	-

Qual Device UA78L05ACPKM3 is qualified at MSL2 260C

Qual Device UA78L033AIPK is qualified at MSL2 260C

Qual Device UA78L15ACPKM3 is qualified at MSL2 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-NPD-2205-099

[1]-EIPD event refer to 4C Report

For questions regarding this notice, e-mails can be sent to the Change Management team or your local Field Sales Representative.

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